

## STP80NF70

## N-channel 68 V, 0.0082 Ω 98 A, TO-220 STripFET™ II Power MOSFET

### Features

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STP80NF70	68 V	< 0.0098 Ω	98 A

- Exceptional dv/dt capability
- 100% avalanche tested

## **Application**

Switching applications

## Description

The STP80NF70 is a N-channel Power MOSFET realized with STMicroelectronics unique STripFET<sup>™</sup> process. It has specifically been designed to minimize input capacitance and gate charge. The device is therefore suitable in advanced high-efficiency switching applications.

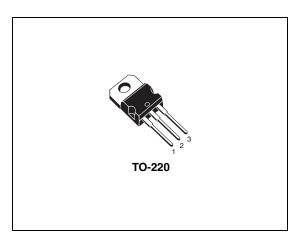


Figure 1. Internal schematic diagram

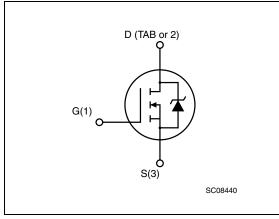


Table 1	Device	
Table 1.	Device	summary

Order code	Marking	Package	Packaging
STP80NF70	80NF70	TO-220	Tube

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## 1 Electrical ratings

Table 2.	Absoluto	movimum	ratinge
Table 2.	Absolute	maximum	ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage ( $V_{GS} = 0$ )	68	V
V <sub>GS</sub>	Gate-source voltage	± 20	V
۱ <sub>D</sub>	Drain current (continuous) at $T_C = 25 \text{ °C}$	98	А
I <sub>D</sub>	Drain current (continuous) at $T_C=100 \ ^{\circ}C$	68	А
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	392	А
P <sub>TOT</sub>	Total dissipation at $T_C = 25 \ ^{\circ}C$	190	W
	Derating factor	1.27	W/°C
dv/dt (2)	Peak diode recovery voltage slope	13	V/ns
E <sub>AS</sub> <sup>(3)</sup>	Single pulse avalanche energy	700	mJ
T <sub>stg</sub>	Storage temperature	-55 to 175	ე∘
TJ	Operating junction temperature	-55 10 175	C

1. Pulse width limited by safe operating area.

2.  $I_{SD} \leq 80$  A, di/dt  $\leq 300$  A/µs,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq T_{JMAX.}$ 

3. Starting  $T_J$  = 25  $^oC,\ I_D$  = 40 A,  $V_{DD}$  = 34 V.

Symbol Parameter		Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.79	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	62.5	°C/W
Τ <sub>Ι</sub>	Maximum lead temperature for soldering purpose <sup>(1)</sup>	300	°C

1. 1.6 mm from case for 10 sec.



## 2 Electrical characteristics

(T<sub>CASE</sub>=25°C unless otherwise specified).

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	68			V
I <sub>DSS</sub>	Zero gate voltage drain current ( $V_{GS} = 0$ )	V <sub>DS</sub> = Max rating, V <sub>DS</sub> = Max rating @125 °C			1 10	μΑ μΑ
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ±20 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 40 A		0.0082	0.0098	Ω

#### Table 4. On/off states

#### Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 40 \text{ A}$	-	60	-	S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> =25 V, f = 1 MHz, V <sub>GS</sub> = 0	-	2550 550 175	-	pF pF pF
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	V <sub>DD</sub> = 34 V, I <sub>D</sub> = 80 A V <sub>GS</sub> =10 V	-	75 17 30	-	nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%.

#### Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD}$ = 34 V, $I_{D}$ = 40 A, R <sub>G</sub> =4.7 $\Omega$ , V <sub>GS</sub> =10 V <i>Figure 13 on page 9</i>	-	17 60 90 75	-	ns ns ns ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		98	А
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		392	А
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 80 \text{ A}, V_{GS} = 0$	-		1.5	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 80 A, di/dt = 100 A/μs, V <sub>DD</sub> = 25 V, T <sub>J</sub> = 150 °C <i>Figure 15 on page 9</i>	-	70 160 4.7		ns nC A

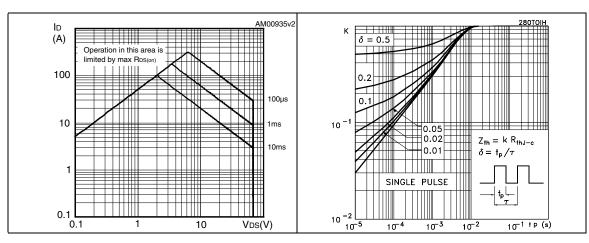
 Table 7.
 Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration=300µs, duty cycle 1.5%



## 2.1 Electrical characteristics (curves)

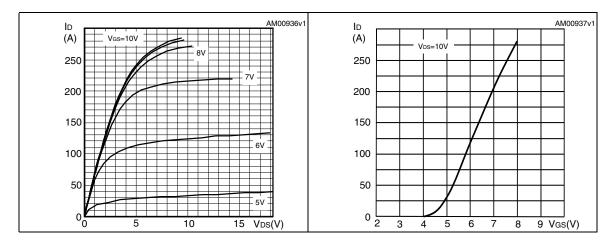


#### Figure 2. Safe operating area

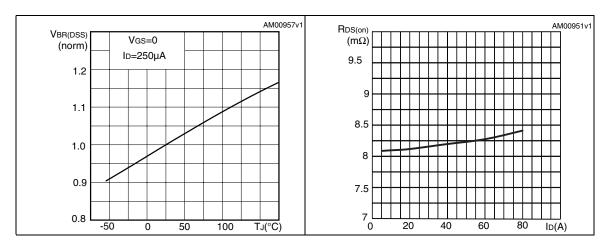






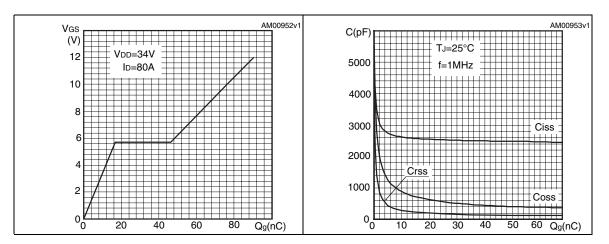




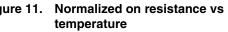


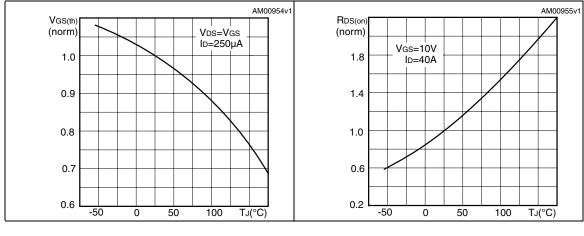
#### Normalized BV<sub>DSS</sub> vs temperature Figure 7. Figure 6. Static drain-source on resistance











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AM00956v1 VSD (V) 1.1 0.9 0.7 0.5 0.5 0.3 0 20 40 60 80 ISD(A)

Figure 12. Source-drain diode forward characteristics



## 3 Test circuits

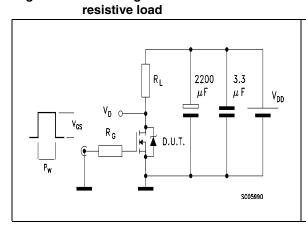


Figure 15. Test circuit for inductive load switching and diode recovery times

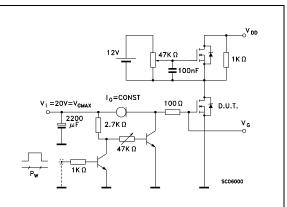


Figure 16. Unclamped inductive load test circuit

L

JUI

D.U.T.

2200

μF

3.3

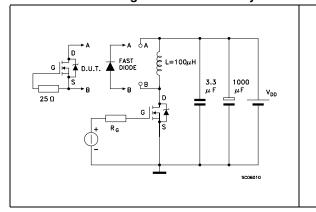
μF

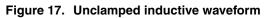
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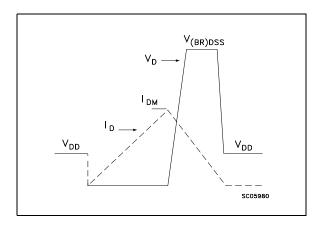
 $V_{\rm DD}$ 

 $v_{D}$   $\diamond$ 

۱<sub>D</sub>







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# Figure 13. Switching times test circuit for Figure 14. Gate charge test circuit

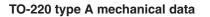
## 4 Package mechanical data

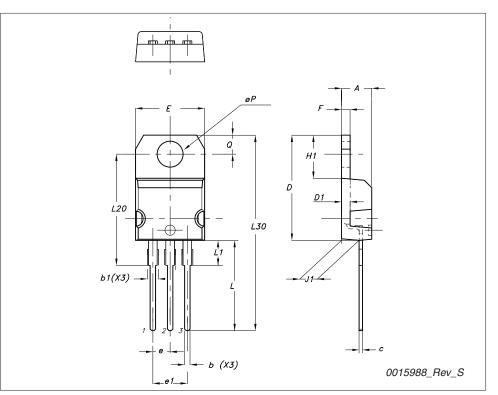
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

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Dim	mm			
	Min	Тур	Max	
А	4.40		4.60	
b	0.61		0.88	
b1	1.14		1.70	
С	0.48		0.70	
D	15.25		15.75	
D1		1.27		
E	10		10.40	
е	2.40		2.70	
e1	4.95		5.15	
F	1.23		1.32	
H1	6.20		6.60	
J1	2.40		2.72	
L	13		14	
L1	3.50		3.93	
L20		16.40		
L30		28.90		
ØP	3.75		3.85	
Q	2.65		2.95	







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## 5 Revision history

#### Table 8.Document revision history

Date	Revision	Changes
11-Jun-2010	1	First release.

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